

**Search Notes**

Application/Control No.

10/790,785

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

MITAMURA ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	231.13, 231.14, 231.17, 237R	12/12/2005	PL
250	237G	12/12/2005	PL
341	13-14	12/12/2005	PL
33	1PT	12/12/2005	PL
356	614-616	12/12/2005	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted S. Allen	6/9/2005	PL
East (see attached) - USPAT, USPG-PUB, EPO, JPO, DERWENT	6/10/2005	PL
East (see attached) - USPAT, USPG-PUB, EPO, JPO, DERWENT	6/13/2005	PL
East (see attached) - USPAT, USPG-PUB, EPO, JPO, DERWENT	6/14/2005	PL
East (see attached) - USPAT, USPG-PUB, EPO, JPO, DERWENT	12/12/2005	PL